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The following listing of claims replaces all prior versions, and listings, of claims in the captioned patent application:

AMENDMENTS TO THE CLAIMS

Docket No. 22409-00288-US

Listing of Claims:

 (Currently Amended) A testing apparatus for <u>concurrently</u> testing at least one-component <u>components</u> of a medical device-and <u>diagnosing problems</u> associated therewith, the testing apparatus comprising:

at-least-one-a plurality of testing station-for-receiving-stations configured to receive and communicably couple to a first component being of a first type and a second component being of a second type, wherein the first component is not of the second type and the second component is not of the first type said at least-one-component and making an electrical and/or inductive connection thereto; and

at least one testing circuit adapted communicably coupled to said plurality of testing stations and configured to concurrently apply at least one a test to each of said first and second components component and to measure the response of the a response of each of said first and second component components to said test;

a memory means for storing data indicative of the response to said test of at least one equivalent component that is known to be operational;

a comparator means for comparing the response of said component to said test to said data and determining whether said response is at least substantially similar to said data; and an output means for outputting a result of said comparison.

2. (Currently Amended) The testing apparatus of elaim—I wherein claim I, wherein the medical device is a cochlear implant system and <u>further wherein</u> said at least one component first and second components that is to undergo testing comprises comprise a cable and/or-and a transmitter coil of said cochlear implant system-adapted to be connected to an external speech processor component of said system.

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3-4. (Cancelled)

(Currently Amended) The testing apparatus of elaim 1 wherein the <u>plurality of testing</u>
stations comprise two or more stations configured to receive two or more types of cables and

further configured to make apparatus is capable of testing at least two different types of cable

and has at least two testing stations for providing an electrical connection to said cables.

6. (Cancelled)

7. (Currently Amended) The testing apparatus of-elaim 6 claim 5 wherein each cable testing

station for each of said two or more types of cables comprises a socket having a shape that is

adapted to receive a plug-one of said two or more types of cables of a particular cable design and

no other, said socket allowing electrical connection to the cable under test.

8. (Currently Amended) The testing apparatus of claim 3-claim 1, wherein said plurality of

testing stations comprise a the apparatus has a single coil testing station configured to test said

transmitter coil.

9. (Currently Amended) The testing apparatus of claim 8 wherein the coil testing apparatus

station comprises a planar area in the first surface of the ease on which the tested transmitter coil

can be placed during testing.

10. (Currently Amended) The testing apparatus of claim 9 wherein the planar area has an indicia

means-indicator provided thereon that provides an indication of where the tested said transmitter coil should be placed to ensure an appropriate test of the tested coil is undertaken during testing.

our should be placed to ensure an appropriate test of the tested con its undertained <u>during testing</u>

11. (Currently Amended) The testing apparatus of claim 10 wherein the indicia means said

indicator comprises a pictorial representation of a transmitter-said transmitter coil.

12. (Cancelled)

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13. (Currently Amended) The testing apparatus of claim 1 wherein a $\underline{\text{first}}$ magnet is positioned

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at or below the planar surface of the case, said first magnet adapted to provide magnetic alienment with a second magnet disposed within a coil-adiacent said transmitter coil under test

and so to maintain the coil in the correct place in a correct position for testing.

and so to maintain the coil in the correct place in a correct position for testing

 $14. \ \ (Currently\ Amended)\ The\ testing\ apparatus\ of\ claim\ 9\ wherein\ each\ tested\ \underline{said\ plurality\ of}$

testing stations further comprises one or more coil testing stations configured to test a cable

extending from the transmission coil has a cable extending therefrom that is also testable by the

testing apparatus.

15. (Currently Amended) The testing apparatus of claim 9 wherein the apparatus is configured

to sense capable of sensing the specific type of components among said two or more types of

components the type of coil, cable, or coil and cable combination that is under test and further

configured to then access from the memory means-component the appropriate stored data for

each said specific type of components use by the comparator means of the apparatus.

16. (Currently Amended) The testing apparatus of claim 1, <u>further comprising a wherein the apparatus further comprises a control circuit configured to control means that controls the overall</u>

apparatus fattier comprises a control <u>offerit configured to control</u> means that controls the control

function of the operations of the testing apparatus.

17. (Currently Amended) The testing apparatus of claim 16 wherein the control means-circuit

comprises a microcontroller.

18. (Currently Amended) The testing apparatus of claim 17 wherein the microcontroller further

acts as control circuit comprises a the memory means component for the testing apparatus.

19. (Currently Amended) The testing apparatus of claim 17 wherein the microcontroller further

comprises a microprocessor having an analogue analog to digital converter (ADC) configured to

digitise digitize the measurements representative of the tested component.

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20. (Currently Amended) The testing apparatus of claim 17 wherein the measurements from said one or more at least one testing eircuits are circuit is in the form of current and voltage levels and levels, and further wherein said data indicative of the response of said equivalent operational eemponent is indicating a desired response to said first test are in the form of voltage and current ranges associated with non-faulty cables and transmitter coils used in cochlear implant systems.

- 21. (Currently Amended) The testing apparatus of claim 1, <u>further comprising an output component for outputting a result of said comparison</u>-wherein the output means comprises one or more lights that are illuminated or turned off in response to the outcome of the test.
- 22. (Currently Amended) The testing apparatus of claim 21 wherein <u>said output component comprise a light configured to a light illuminates illuminate</u> if the tested component passes the test and test fails to illuminate if the tested component is inoperative or faulty.
- (Currently Amended) The testing apparatus of elaim 21 claim 22, wherein the said light is a light emitting diode (LED).
- 24. (Currently Amended) A method of <u>concurrently</u> testing at least one component components of a medical device and diagnosing problems associated therewith comprising the step of <u>using a testing apparatus having a plurality of testing stations</u>, comprising:

receiving, by the testing apparatus, a first component being of a first type and a second component being of a second type, wherein the first component is not of the second type and the second component is not of the first type;

communicably coupling making an electrical and/or inductive connection between the first and second said components component and at least one with a first and second of said plurality of testing station of the stations, respectively, of the testing apparatus as defined in claim 1 apparatus; and

performing a test on said first and second components-component concurrently.

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25. (New) The method of testing of claim 24, wherein said performing a test comprises:

applying a first and second test to the first and second components;

measuring a response to each said applied first and second test;

retrieving stored data comprising desired response data for each said first and second test;

and

comparing the measured response to the desired response for each said first and second

test.

26. (New) The method of testing of claim 24, wherein the testing apparatus and at least one of the two components each have corresponding magnets, and further wherein said receiving at

least two of said two or more types of components further comprises:

magnetically coupling at least one of said two components to the testing apparatus.

27. (New) The method of testing of claim 25, further comprising:

sensing the specific type among the two or more types of components.

wherein said retrieved data corresponds to the sensed type of component from a plurality of stored data for each of the two or more types of components.

28. (New) The testing apparatus of claim 1, further comprising a memory component

configured to store data indicating a desired response to said first test.

29. (New) The testing apparatus of claim 1, further comprising a comparator circuit configured to compare said measured response to a desired response stored in a memory component and to

generate output indicating whether said measured response is at least substantially similar to said

desired response.